DATA SHEET 74F191 Up/down binary counter with reset and ripple clock **Product specification** 1995 Jul 17

INTEGRATED CIRCUITS

IC15 Data Handbook





74F191

FEATURES

- High speed –125MHz typical f_{MAX}
- Synchronous, reversible counting
- 4-Bit binary
- Asynchronous parallel load capability
- Cascadable without external logic
- Single up/down control input

DESCRIPTION

The 74F191 is a 4-bit binary counter. It contains four edge-triggered master/slave flip-flops with internal gating and steering logic to provide asynchronous preset and synchronous count-up and count-down operations.

Asynchronous parallel load capability permits the counter to be preset to any desired number. Information present on the parallel data inputs ($D_0 - D_3$) is loaded into the counter and appears on the outputs when the Parallel Load (PL) input is Low. This operation overrides the counting function. Counting is inhibited by a High level on the count enable (CE) input. When CE is Low, internal state changes are initiated. Overflow/underflow indications are provided by two types of outputs, the Terminal Count (TC) and Ripple Clock (RC).

The TC output is normally Low and goes High when: 1) the count reaches zero in the countdown mode or 2) reaches "15" in the count up mode. The TC output will remain High until a state change occurs, either by counting or presetting, or until \overline{U}/D is changed. TC output should not be used as a clock signal because it is subject to decoding spikes. The TC signal is used internally to enable the \overline{RC} output. When TC is High and \overline{CE} is Low, the \overline{RC} follows the clock pulse. The \overline{RC} output essentially duplicates the Low clock pulse width, although delayed in time by two gate delays.

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

T T		1
D ₁ 1	Ŭ	16 VCC
Q1 2		15 D ₀
Q ₀ 3		14 CP
CE 4		13 RC
Ū/D 5		12 TC
Q ₂ 6		11 PL
Q ₃ 7		10 D ₂
GND 8		9 D3
		J
	SF	00729

ТҮРЕ	TYPICAL f _{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F191	125MHz	40mA

ORDERING INFORMATION

PIN CONFIGURATION

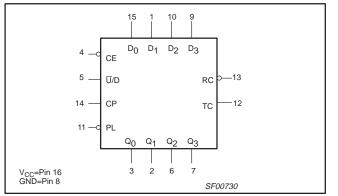
DESCRIPTION	$\begin{array}{l} \text{COMMERCIAL RANGE} \\ \text{V}_{\text{CC}} = 5\text{V} \pm 10\%, \\ \text{T}_{\text{amb}} = 0^{\circ}\text{C} \text{ to } + 70^{\circ}\text{C} \end{array}$	PKG DWG #
16-pin plastic DIP	N74F191N	SOT38-4
16-pin plastic SO	N74F191D	SOT109-1

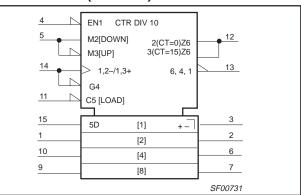
PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D ₀ - D ₃	Data inputs	1.0/1.0	20µA/0.6mA
CE	Count enable input (active Low)	1.0/3.0	20µA/1.8mA
СР	Clock pulse input (active rising edge)	1.0/1.0	20µA/0.6mA
PL	Asynchronous parallel load control input (active Low)	1.0/1.0	20µA/0.6mA
Ū/D	Up/down count control input	1.0/1.0	20µA/0.6mA
Q ₀ - Q ₃	Flip-flop outputs	50/33	1.0mA/20mA
RC	Ripple clock output (active low)	50/33	1.0mA/20mA
ТС	Terminal count output	50/33	1.0mA/20mA

NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20µA in the High state and 0.6mA in the Low state.

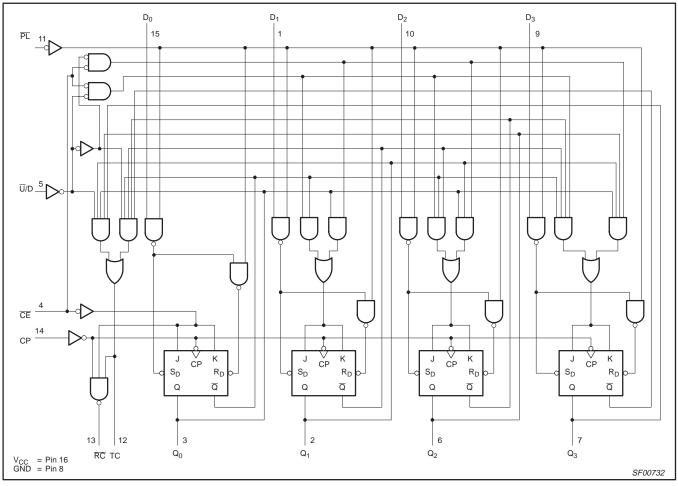
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LOGIC SYMBOL





LOGIC DIAGRAM



LOGIC SYMBOL (IEEE/IEC)

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MODE SELECT — FUNCTION TABLE

	INPUTS				OUTPUTS	OPERATING MODE
PL	Ū/D	CE	СР	D _n	Q _n	
L	X X	X X	X X	L H	L H	Parallel load
Н	L	I	\uparrow	Х	Count up	Count up
Н	Н	I	\uparrow	Х	Count down	Count down
Н	Х	Н	Х	Х	No change	Hold (do nothing)

TC AND RC FUNCTION TABLE

	INPUTS			TERMINAL COUNT STATE			OUTF	PUTS
Ū/D	CE	СР	Q ₀	Q ₁	Q ₂	Q ₃	тс	RC
н	Н	Х	Н	Н	Н	Н	L	Н
L	н	х	н	н	н	н	н	н
L	L	U	н	н	н	н	Н	ъ
L	н	Х	L	L	L	L	L	Н
н	н	х	L	L	L	L	н	н
н	L	υ	L	L	L	L	Н	U

H = High voltage level steady state L = Low voltage level steady state

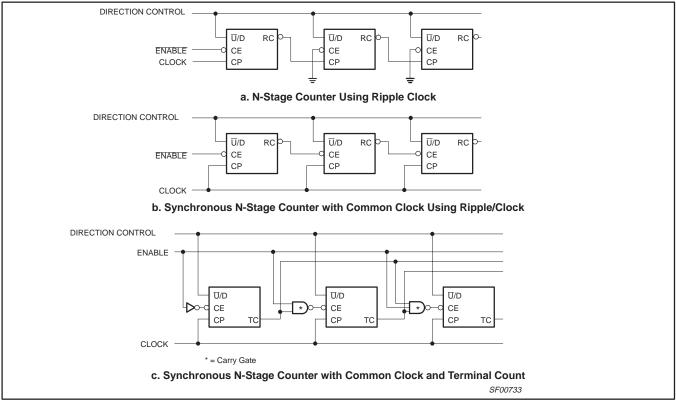
X = Don't care

⊥ = Low pulse

 $\begin{array}{l} \uparrow \\ \uparrow \\ = \\ Low-to-High \ clock \ transition \\ I \\ = \\ Low \ voltage \ level \ one \ set-up \ time \ prior \ to \ the \ Low-to-High \ clock \ transition \\ \end{array}$

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APPLICATIONS





The 74F191 simplifies the design of multi-stage counters, as indicated in Figure 1, each \overline{RC} output is used as the clock input for the next higher stage. When the clock source has a limited drive capability this configuration is particularly advantageous, since the clock source drives only the first stage. It is only necessary to inhibit the first stage to prevent counting in all stages, since a High signal on \overline{CE} inhibits the \overline{RC} output pulse as indicated in the Mode Select Table. The timing skew between state changes in the first and last stages is represented by the cumulative delay of the clock as it ripples through the preceding stages. This is a disadvantage of the configuration in some applications.

Figure 1b shows a method of causing state changes to occur simultaneously in all stages. The RC output signals propagate in

ripple fashion and all clock inputs are driven in parallel. The Low state duration of the clock in this configuration must be long enough to allow the negative-going edge of the $\overline{\text{RC}}$ signal to ripple through to the last stage before the clock goes High. Since the $\overline{\text{RC}}$ output of any package goes High shortly after its clock input goes High, there is no such restriction on the High state duration of the clock.

In Figure 1c, the configuration shown avoids ripple delays and their associated restrictions. The combined TC signals from all the preceding stages forms the CE input signal for a given stage. An enable signal must also be included in each carry gate in order to inhibit counting. The TC output of a given stage is not affected by its own CE, therefore, the simple inhibit scheme of Figure 1a and 1b does not apply.

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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5.0	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to +V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	٥C
T _{stg}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		UNIT		
STMBOL	PARAMETER	Min	Nom	Max	UNIT
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
VIL	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _{amb}	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITI			LIMITS		UNIT
STMBOL	PARAMEI	PARAMETER		TEST CONDITIONS ¹			Max	UNIT
V	High-level output voltage		V _{CC} = Min, V _{IL} = Max,	$\pm 10\% V_{CC}$	2.5			V
V _{OH}	Figh-level output voltage	;	$I_{OH} = Max, V_{IH} = Min$	±5%V _{CC}	2.7	3.4		V
M			$V_{CC} = Min, V_{II} = Max,$	±10%V _{CC}		0.30	0.50	V
V _{OL}	Low-level output voltage	Low-level output voltage		±5%V _{CC}		0.30	0.50	V
V _{IK}	Input clamp voltage		$V_{CC} = Min, I_I = I_{IK}$			-0.73	-1.2	V
l _l	Input current at maximur	n input voltage	$V_{CC} = Max, V_I = 7.0V$				100	μA
I _{IH}	High-level input current		$V_{CC} = Max, V_I = 2.7V$				20	μA
I _{IL}	Low-level input current	CE					-1.8	mA
		Others	$V_{CC} = Max, V_I = 0.5V$				-0.6	mA
I _{OS}	Short-circuit output curre	nt ³	V _{CC} = Max		-60		-150	mA
I _{CC}	Supply current ⁴ (total)		V _{CC} = Max			40	55	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

4. Measure I_{CC} all inputs grounded and all outputs open.

^{2.} All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$. 3. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

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			LIMITS					
SYMBOL	PARAMETER	TEST CONDITIONS	T _{amb} = +25°C V _{CC} = +5.0V C _L = 50pF, R _L = 500Ω			T _{amb} = 0°C V _{CC} = +5 C _L = 50pF,	UNIT	
			Min	Тур	Max	Min	Max	
f _{MAX}	Maximum clock frequency to Qn outputs	Waveform 1	100	125		90		MHz
f _{MAX}	Maximum clock frequency to RC outputs	Waveform 1	85	95		75		MHz
t _{PLH}	Propagation delay	Waveform 1	2.5	4.5	8.0	2.0	8.5	ns
t _{PHL}	CP to Q _n		5.0	7.5	11.5	5.0	12.0	ns
t _{PLH}	Propagation delay	Waveform 1	6.5	9.0	12.5	6.0	13.0	ns
t _{PHL}	CP to TC		6.0	8.0	11.0	6.0	12.0	ns
t _{PLH}	Propagation delay	Waveform 2	2.5	4.5	7.5	2.0	8.0	ns
t _{PHL}	CP to RC		3.0	5.0	7.5	2.5	8.0	ns
t _{PLH}	Propagation delay	Waveform 2	2.0	4.0	7.0	2.0	7.5	ns
t _{PHL}	CE to RC		3.0	5.0	7.5	3.0	8.0	ns
t _{PLH}	Propagation delay	Waveform 2	8.0	11.0	16.0	8.0	17.0	ns
t _{PHL}	U/D to RC		4.5	7.5	10.5	4.0	11.0	ns
t _{PLH}	Propagation delay	Waveform 4	4.0	6.5	9.5	3.0	10.5	ns
t _{PHL}	Ū/D to TC		3.0	6.0	9.5	3.0	10.0	ns
t _{PLH} t _{PHL}	Propagation delay D_n to Q_n	Waveform 3	2.0 6.5	4.0 9.0	7.0 12.0	1.5 6.5	7.5 13.0	ns ns
t _{PLH}	Propagation delay	Waveform 3	5.5	9.5	13.0	5.0	14.0	ns
t _{PHL}	D _n to TC	Waveform 4	6.5	9.5	13.0	6.0	14.0	ns
t _{PLH}	Propagation delay D_n to \overline{RC}	Waveform 3	6.0	14.0	18.0	6.0	19.5	ns
t _{PHL}		Waveform 4	6.0	11.0	13.5	6.0	15.0	ns
t _{PLH} t _{PHL}	$\frac{\text{Propagation delay}}{\text{PL to } Q_n}$	Waveform 5	4.5 5.5	6.5 8.0	9.5 11.5	4.0 5.0	10.5 12.0	ns ns
PLH	Propagation delay	Waveform 5	5.5	8.5	12.0	5.5	13.0	ns
PHL	PL to TC		6.0	10.5	13.5	6.0	14.5	ns
^t PLH	Propagation delay	Waveform 5	8.5	16.0	18.5	8.5	21.0	ns
^t PHL	PL to RC		7.5	10.0	13.0	7.0	13.5	ns

AC ELECTRICAL CHARACTERISTICS

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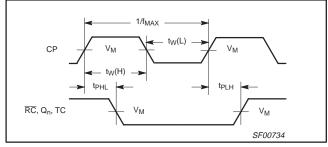
AC SETUP REQUIREMENTS

					LIMIT	S		
SYMBOL	PARAMETER	TEST CONDITIONS	ST CONDITIONS $\begin{array}{c} T_{amb} = +25^{\circ}C \\ V_{CC} = +5.0V \\ C_{L} = 50pF, R_{L} = 500 \end{array}$			T _{amb} = 0°C V _{CC} = +5. C _L = 50pF,	UNIT	
			Min	Тур	Max	Min	Max	
t _s (H) t _s (L)	Setup time, High or Low D _n to PL	Waveform 6	4.5 4.5			5.0 5.0		ns ns
t _h (H) t _h (L)	Hold time, High or Low D _n to PL	Waveform 6	2.0 2.0			2.0 2.0		ns ns
t _s (L)	Setup time, Low CE to CP	Waveform 6	10.0			10.0		ns
t _h (L)	Hold time, Low CE to CP	Waveform 6	0			0		ns
t _s (H) t _s (L)	Setup time, High or Low \overline{U}/D to CP	Waveform 6	12.0 12.0			12.0 12.0		ns ns
t _h (H) t _h (L)	Hold time, High or Low \overline{U}/D to CP	Waveform 6	0 0			0 0		ns ns
t _w (H) t _w (L)	CP Pulse width, High or Low	Waveform 1	3.5 6.0			3.5 6.0		ns ns
t _w (L)	PL Pulse width, Low	Waveform 5	6.0			6.0		ns
t _{rec}	Recovery time, PL to CP	Waveform 5	6.0			6.0		ns

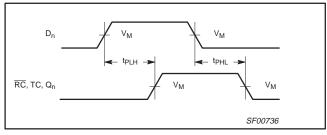
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AC WAVEFORMS

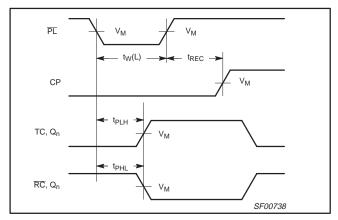
NOTE: For all waveforms, $V_M = 1.5V$



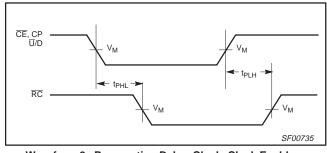
Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency.



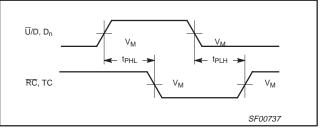
Waveform 3. Propagation Delay, Non-Inverting Path



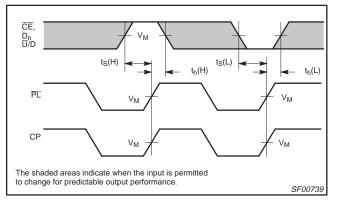
Waveform 5. Parallel Load Pulse Width, Parallel Load to Output Delay and Parallel Load to Clock Recovery Time



Waveform 2. Propagation Delay, Clock, Clock Enable or Up/Down to Ripple Clock Output



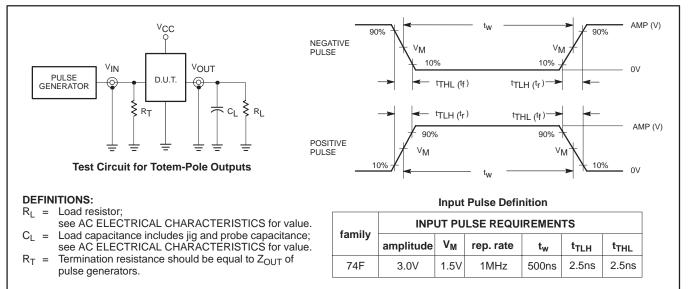
Waveform 4. Propagation Delay, Inverting Path



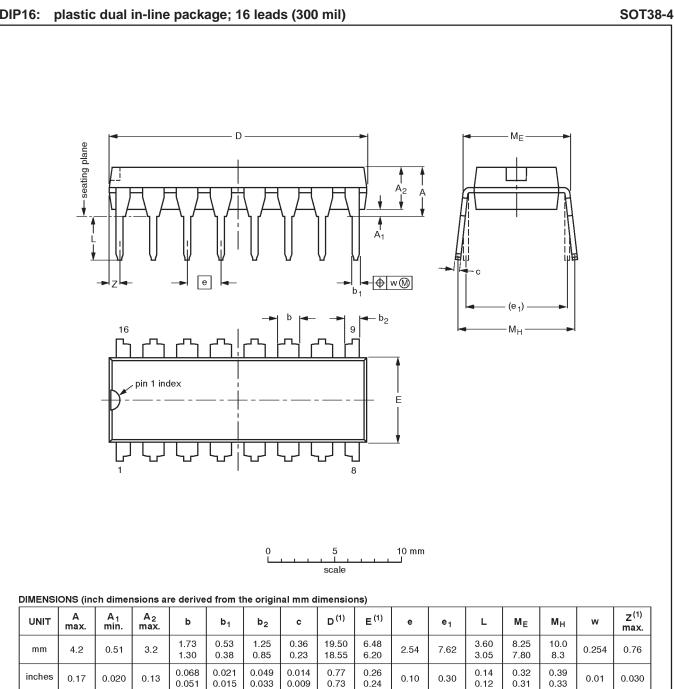
Waveform 6. Data Set Up and Hold Times

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TEST CIRCUIT AND WAVEFORM



SF00006



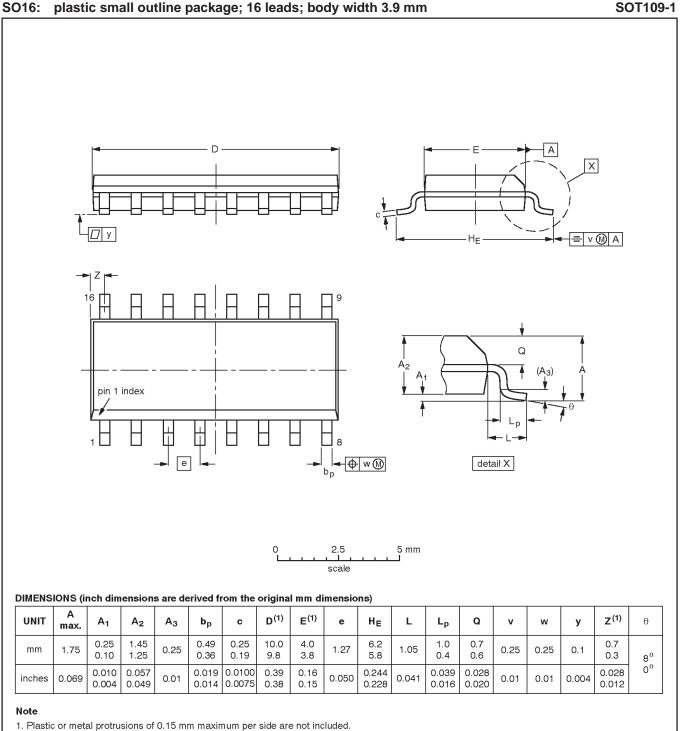
DIP16:

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE REFERENCES	EUROPEAN	ISSUE DATE				
VERSION	IEC	JEDEC	EIAJ PRO	PROJECTION	ISSUE DATE	
SOT38-4						-92-11-17- 95-01-14

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OUTLINE VERSION	REFERENCES				EUROPEAN	ISSUE DATE
	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT109-1	076E07S	MS-012AC				-95-01-23 97-05-22
				•		

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NOTES

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Data sheet status

Data sheet status	Product status	Definition ^[1]	
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.	
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.	
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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